



Contribution ID: 232

Type: **Oral (Non-Student) / orale (non-étudiant)**

Canadian Charged Particle Accelerator Consortium

Tuesday 17 June 2014 10:30 (15 minutes)

Many materials analysis techniques rely on the 'particle in - particle out' principle, where a source produces precisely controlled probe particles that interact with a sample and a detector characterizes the scattered or transmitted probe particles, providing information on the nature and structure of the sample under study. Examples of probe particles are electrons (electron microscopes), photons (synchrotrons), neutrons (indeed), and, in our case, ions.

The Canadian Charged Particle Accelerator Consortium (CCPAC, <http://ion.lps.umontreal.ca/>) is a national facility, accessible for all Canadian and many international researchers, which provides ion beams for materials analysis and modification. In this contribution, we will present the suite of thin film analysis techniques available at CCPAC, showcase their strengths and limitations, and give some recent examples of analyses performed in aid of research in the field of physics of advanced materials.

Author: ROORDA, Sjoerd (U)

Co-authors: Prof. SCHIETTEKATTE, François (Université de Montréal); Prof. GONCHAROVA, Lyudmila (University of Western Ontario)

Presenter: ROORDA, Sjoerd (U)

Session Classification: (T1-4) Mass Spectrometry and Nuclear Structure - DNP / Spectrométrie de masse et structure nucléaire - DPN

Track Classification: Instrumentation and Measurement Physics / Physique des instruments et mesures (DIMP-DPIM)